

October 2007

FDMS8660AS

N-Channel PowerTrench[®] SyncFETTM 30V, 49A, 2.1m Ω

Features

- Max $r_{DS(on)} = 2.1 \text{m}\Omega$ at $V_{GS} = 10 \text{V}$, $I_D = 28 \text{A}$
- Max $r_{DS(on)} = 3.1 \text{m}\Omega$ at $V_{GS} = 4.5 \text{V}$, $I_D = 22 \text{A}$
- Advanced Package and Silicon combination for low r_{DS(on)} and high efficiency
- SyncFET Schottky Body Diode
- MSL1 robust package design
- RoHS Compliant

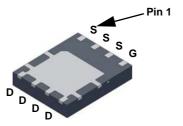


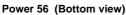
General Description

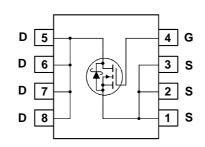
The FDMS8660AS has been designed to minimize losses in power conversion application. Advancements in both silicon and package technologies have been combined to offer the lowest $r_{\text{DS}(\text{on})}$ while maintaining excellent switching performance. This device has the added benefit of an efficient monolithic Schottky body diode.

Applications

- Synchronous Rectifier for DC/DC Converters
- Notebook Vcore/ GPU low side switch
- Networking Point of Load low side switch
- Telecom secondary side rectification







MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
V_{DS}	Drain to Source Voltage			30	V
V_{GS}	Gate to Source Voltage			±20	V
I _D	Drain Current -Continuous (Package limited)	T _C = 25°C		49	
	-Continuous (Silicon limited) T _C = 25°C			179	^
	-Continuous	T _A = 25°C	(Note 1a)	28	A
	-Pulsed			200	
E _{AS}	Single Pulse Avalanche Energy		(Note 2)	726	mJ
C	Power Dissipation	T _C = 25°C		104	W
P_{D}	Power Dissipation	T _A = 25°C	(Note 1a)	2.5	VV
T _J , T _{STG}	Operating and Storage Junction Temperature R	ange		-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.2	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	5,44

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS8660AS	FDMS8660AS	Power 56	13" 12mm		3000units

Units

Electrical Characteristics T_J = 25°C unless otherwise noted

Parameter

Off Char	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 1mA$, $V_{GS} = 0V$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 10mA, referenced to 25°C		27		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24V, V_{GS} = 0V$			500	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA

Test Conditions

On Characteristics

Symbol

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 1mA$	1.0	1.7	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I _D = 10mA, referenced to 25°C		-5		mV/°C
		$V_{GS} = 10V, I_D = 28A$		1.7	2.1	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 4.5V, I_D = 22A$		2.3	3.1	mΩ
		$V_{GS} = 10V$, $I_D = 28A$, $T_J = 125$ °C		2.3	3.1	
9 _{FS}	Forward Transconductance	$V_{DD} = 10V, I_D = 28A$		167		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 45V V 0V	4410	5865	pF
Coss	Output Capacitance	$V_{DS} = 15V, V_{GS} = 0V,$ $f = 1MHz$	2305	3065	рF
C _{rss}	Reverse Transfer Capacitance	1 - 1101112	185	280	pF
R _a	Gate Resistance	f = 1MHz	1.2		Ω

Switching Characteristics

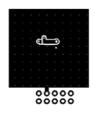
t _{d(on)}	Turn-On Delay Time	., .=.,	16	29	ns
t _r	Rise Time	$V_{DD} = 15V, I_{D} = 28A,$ $V_{GS} = 10V, R_{GEN} = 6\Omega$	8	16	ns
t _{d(off)}	Turn-Off Delay Time	V _{GS} = 10V, K _{GEN} = 012	42	68	ns
t _f	Fall Time		5	10	ns
Q_g	Total Gate Charge	V _{GS} = 0V to 10V	59	83	nC
Qg	Total Gate Charge	$V_{GS} = 0V \text{ to } 4.5V$ $V_{DD} = 15V,$ $I_{D} = 28A$	30	42	nC
Q _{gs}	Gate to Source Charge	I _D = 20A	12		nC
Q_{gd}	Gate to Drain "Miller" Charge		5.2		nC

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0V$, $I_S = 2A$ (Note 3)		0.4	0.7	V
t _{rr}	Reverse Recovery Time	$I_{\rm E} = 28$ A, di/dt = 300A/µs		46	74	ns
Q_{rr}	Reverse Recovery Charge	I _F = 28A, αl/αt = 300A/μs		67	108	nC

NOTES

^{1.} R_{0,1/A} is determined with the device mounted on a 1in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0,1/C} is guaranteed by design while R_{0,1/C} is determined by the user's board design.



a. 50°C/W when mounted on a 1 in² pad of 2 oz copper.

b. 125°C/W when mounted on a minimum pad of 2 oz copper.



^{2.} Starting T_J = 25°C, L = 3mH, $I_{\mbox{\scriptsize AS}}$ = 22A, $V_{\mbox{\scriptsize DD}}$ = 30V, $V_{\mbox{\scriptsize GS}}$ = 10V.

^{3.} Pulse Test: Pulse Width < 300μ s, Duty cycle < 2.0%.

Typical Characteristics $T_J = 25$ °C unless otherwise noted

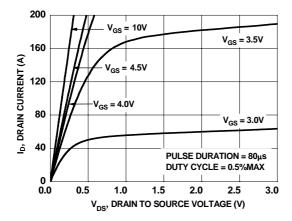


Figure 1. On-Region Characteristics

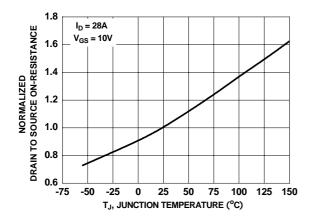


Figure 3. Normalized On-Resistance vs Junction Temperature

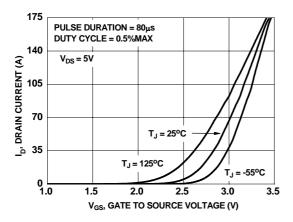


Figure 5. Transfer Characteristics

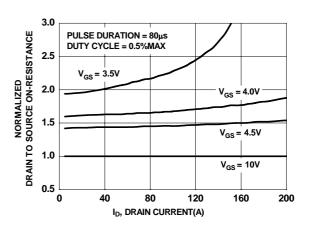


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

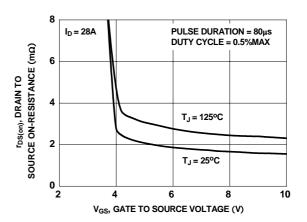


Figure 4. On-Resistance vs Gate to Source Voltage

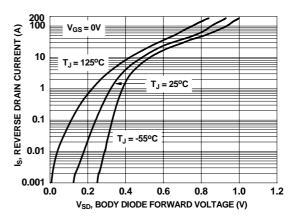


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

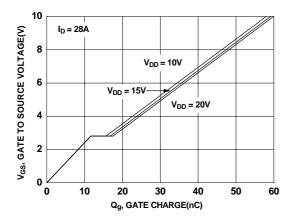


Figure 7. Gate Charge Characteristics

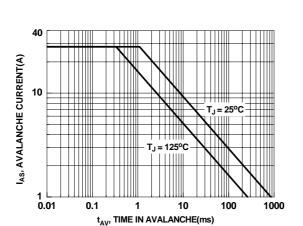


Figure 9. Unclamped Inductive Switching Capability

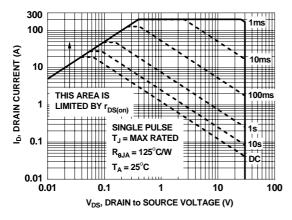


Figure 11. Forward Bias Safe Operating Area

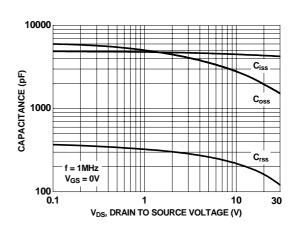


Figure 8. Capacitance vs Drain to Source Voltage

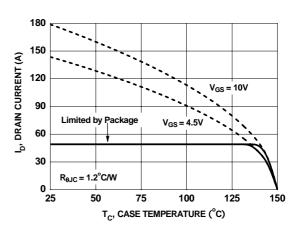


Figure 10. Maximum Continuous Drain Current vs Case Temperature

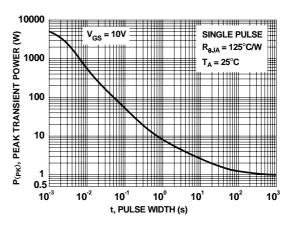


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25$ °C unless otherwise noted

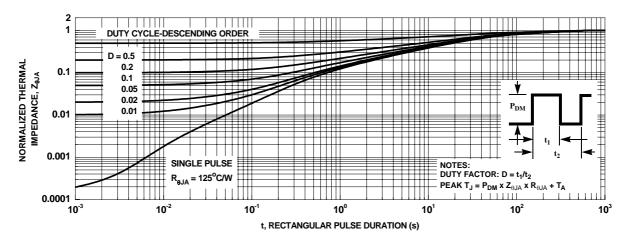


Figure 13. Transient Thermal Response Curve

Typical Characteristics (continued)

SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 14 shows the reverse recovery characteristic of the FDMS8660AS.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

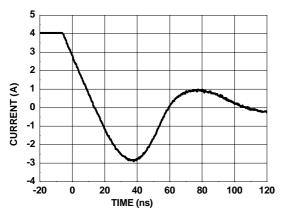


Figure 14. FDMS8660AS SyncFET Body Diode Reverse Recovery Characteristics

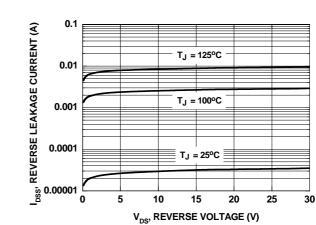
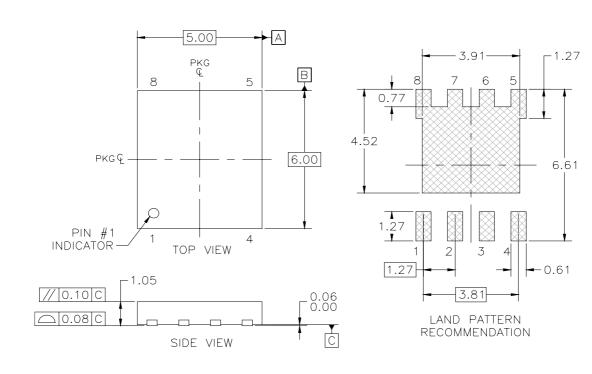
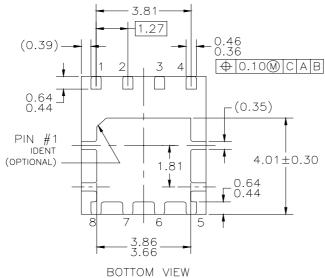


Figure 15. SyncFET Body Diode Reverse Leakage vs Drain to Source Voltage





NOTES: UNLESS OTHERWISE SPECIFIED

A) ALL DIMENSIONS ARE IN MILLIMETERS.

- А) В)
- NO JEDEC REFERENCE AS OF FEBRUARY 2006 DIMENSIONING AND TOLERANCING PER ASME Y14.5M 1994

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